

*how big can you dream?*<sup>™</sup>



# Future Directions in Mixed-Signal Behavioral Modeling

**Ken Kundert**  
**October 2002**

*Mixed-signal behavioral modeling is starting to take off ...*

- Standard languages are here
  - Verilog-A, Verilog-AMS, VHDL-AMS
- Simulators are ready or soon will be ...
  - Spectre and AMS Designer from Cadence
  - Advance-MS from Mentor
  - More than ten others
- Mixed-signal IP is becoming available with behavioral models
  - Barcelona, Neoliner, AMI Semi, Tality, etc.
- Slowly building up a supply of trained modeling engineers

# Emerging Trends



*The following are expected to be focus areas for the next few years*

- Top-down design
- RF
- MEMS
- Compact modeling

*how big can you dream?™*



# Top-Down Design

# Design Challenge: Size and Complexity



- Increasing complexity as circuits become larger
  - Increasing integration
    - To reduce cost, size, weight, and power dissipation
  - Digitalization
    - Both digital information and digital implementation
- Increasing complexity of signal processing
  - Implementation of algorithms in silicon
    - Adaptive circuits, error correction, PLL's, etc.
- Designers must improve their productivity to keep up

Slides from EPD 2001, AACD 2000

# Productivity: Improving CAD is not Enough



*“Fundamental improvements in design methodology and CAD tools will be required to manage the overwhelming design and verification complexity”*

Dr. H. Samueli, co-chairman and CTO, Broadcom Corp. Invited Keynote Address, "Broadband communication ICs: enabling high-bandwidth connectivity in the home and office", *Slide supplement 1999 to the Digest of Technical Papers*, pp. 29-35, International Solid State Circuits Conference, Feb 15-17, 1999, San Francisco, CA

- Huge productivity ratio between design groups
  - As much as 14x (Collett International, 1998)
- In a fast moving market
  - Cannot overcome this disparity in productivity by working harder
  - Must change the way design is done
- Cause of poor productivity: Using a bottom-up design style
  - Problems are found late in design cycle, causing substantial redesign
  - Simulation is expensive, and so usually inadequate
  - Inadequate verification requires silicon prototypes
  - Today's designs are too complex for bottom-up design style
  - Too many serial dependencies

# What is Needed



- To handle larger and more complex circuits
  - Need better productivity
  - Need divide and conquer strategy
- To address time-to-market
  - Must effectively utilize more designers
  - Must reorganize design process
    - More independent tasks
    - Reduce number of serial steps



# The Solution



- A formal top-down design process ...
  - That methodically proceeds from architecture to transistor level
  - Where each level is fully designed before proceeding to next level
  - Where each level is fully leveraged in design of next level
  - Where each move is verified before proceeding
- Careful verification planning involving ...
  - System verification through simulation
  - Mixed-level verification through simulation
  - A modeling plan that maximizes efficacy and speed of simulation
  - Full chip simulation only when no alternatives exist
- Test development that proceeds in parallel with design

- Rapidly explore and verify architecture via simulation
  - Using Verilog-AMS provides a smooth transition to circuit level
  - VHDL-AMS or Simulink could also be used, but more cumbersome
- Provides greater understanding of system early in design process
  - Rapid optimization of architecture
  - Discard unworkable architectures early
- Moves simulation to front of design process
  - Simulation is much faster
  - Block specs driven by system simulation

- Find appropriate interfaces and partition
  - Clever partitioning can be source of innovation
    - Joining normally distinct blocks can payoff in better performance
      - LO and mixer, S&H and ADC, etc.
  - Budget specifications for blocks
    - System simulation and experience used to set block specifications
  - Document interfaces
- Formal partitioning supports concurrent design
  - Better communication
  - Design of blocks proceeds in parallel
  - Allows more engineers to work on the same project

# Pin-Accurate Top-Level Schematic



- Develop pin-accurate top-level schematic
  - Behavioral models represent the blocks
  - Faithfully represents block interfaces
    - Levels, polarities, offsets, drive strengths, loading, timing, etc.
- Distribute to every member of the team
  - Acts as executable specification and test bench
  - Acts as DUT for test program development
- Owned by chip architect
  - Cannot be changed without agreement from affected team members
  - Changes to interfaces not official until TLS updated and redistributed

# Mixed-Level Simulation (MLS)



- Verify circuit blocks in context of system
  - Individual blocks simulated at transistor level
  - Rest of system at behavioral level
- Simulate with pin-accurate block models
  - Verifies block interface specifications
  - Eases integration of completed blocks
- Only viable approach to verify complex systems
  - Can improve simulation speed by order of magnitude over full transistor level simulation

# Simulation and Modeling Plans



- Identify areas of concern, develop verification plans
  - Maximize use and efficacy of system-and mixed-level simulation
  - Minimize need for full-chip transistor-level simulation
- Modeling plan developed from simulation plan
  - There may be several models for each block
    - Several simple models often better than one complex one
    - Consider loading, bias levels and headroom, etc.
- Developed and enforced by the chip architect
- Up front planning results in ...
  - More complete and efficient verification
  - Fewer design iterations

# SPICE Simulation



- Use selectively as needed
  - Mixed-level simulation
    - Verify blocks in context of system
  - Hot spots
  - Critical paths
  - Start-up behavior
- The idea is not to eliminate SPICE simulation, but to ...
  - Reduce the time spent in SPICE simulation while ...
  - Increasing the effectiveness of simulation in general

# Top-Down Design Is ...



- A way of trading ...
  - An up-front investment in planning and modeling
- For ...
  - A well controlled design process
    - More predictable
    - Fewer unpleasant surprises
    - Fewer design iterations
  - More parallelism



# Top-Down Design ...



- Is not going to happen on its own
- It is a formal top-down design process that requires a serious commitment through out the entire design process
- It requires a substantial investment in education and infrastructure
- Any design group that attempts it without adequate training, management support, and planning is likely to fail
- It is much easier the second time around

# Top-Down Design Impediments



- Lack of acceptance
  - Designers use bottom-up design or lazy top-down design
  - They do not follow formal top-down design principles
    - Partition design using well specified and verified interfaces
    - Develop verification and modeling plans in advance
    - Avoid unverified translations
      - Mixed-level simulation
- Lack of qualified engineers
  - Need strong modeling, simulation, and application background

# What is Needed



- A long term perspective
- Extensive model libraries
  - Reduced barrier to entry
  - Learn by example
- Improved education and training
  - Must train modeling
  - Must train top-down design
  - Must train both inside and outside universities
    - University classes, workshops, books, articles, etc.
- Model extraction and fitting tools

**It Can Happen,  
Stranger Things Have**



# Bears muzzle No. 12 Huskies

**CAL DEFEATS WASHINGTON FOR  
1<sup>ST</sup> TIME IN 26 YEARS**

San Jose Mercury News, 6 October 2002

*how big can you dream?™*



# RF Design

# Modeling Challenges in RF Design



- High-level modeling
- Transition from high-level model to implementation
- Distributed component modeling

# High-Level Modeling of RF Systems



- Today
  - Simulators (Matlab & Simulink, Ptolemy, SPW)
  - Spreadsheets (Excel)
- Missing in action
  - VHDL-AMS
  - Verilog-AMS
  - Verilog-A

# What is Working Today, What is Not



- + RF model libraries (generic & standards)
- + RF analysis (test benches and measurement)
- Smooth transition to implementation
  
- AMS languages can help solve implementation issue  
*But must catch up in libraries & analysis*



# Why Use Behavioral Modeling?

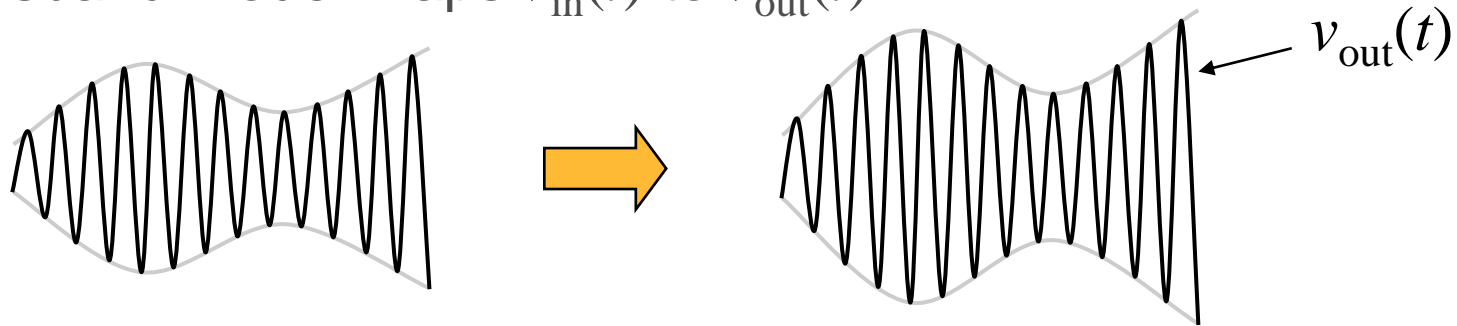


- Behavioral models translate RF metrics into system metrics
  - Through simulation
- Standard RF metrics
  - Gain,  $iIP_3$ , noise figure
- Standard system metrics
  - BER, EVM, ACPR
  - Determining these metrics is very compute intensive
  - Simulations must be very fast

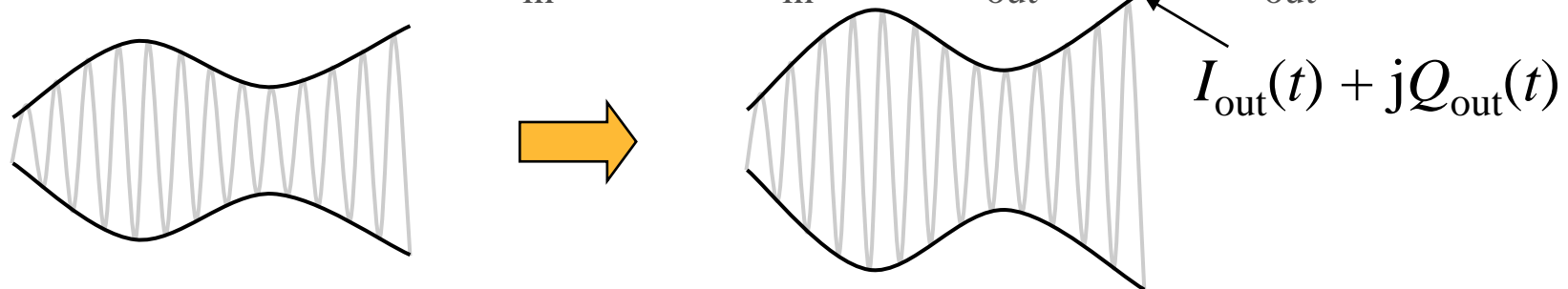
Slides derived from those of Jess Chen (BMAS 2001)

# Suppressed Carrier Modeling

- Assume signals of the form  $v(t) = \text{Re}\{(I(t) + jQ(t))e^{j\omega t}\}$
- Passband model maps  $v_{\text{in}}(t)$  to  $v_{\text{out}}(t)$



- Baseband model maps  $I_{\text{in}}(t)$  and  $Q_{\text{in}}(t)$  to  $I_{\text{out}}(t)$  and  $Q_{\text{out}}(t)$



- More efficient because time point density is much lower

# Two Types of RF Models



- Passband Models
  - Does not suppress the carrier
  - Good for implementation and validation
  - Too slow for architectural exploration
- Baseband Equivalent Models
  - Highly effective at exploring the architectural space.
  - Specify components in terms of RF metrics.
  - Measure performance in terms of system metrics.

# Transition to Implementation



- Use baseband-equivalent models for architectural exploration
- Use passband models in transition to implementation
  - Allows more detail in the model
  - Compatible with transistor-level simulation
- Co-simulate baseband and passband models
  - Use modulators and de-modulators as interface elements
- Issue
  - Baseband models pass 2 numbers (I & Q) per wire
    - Perhaps more, harmonics, impedance, etc.
  - Verilog-A/MS does not support this

# What is Needed



- Extension of Verilog-A/MS to support composite signals
- Library of self-consistent passband and baseband models
- Application support
  - Standard-based test benches
  - RF analyses and measurements

- Generally described in the frequency-domain
  - Naturally compatible with harmonic balance
  - More work needed to support in transient-based simulators
- VHDL-FD or VHDL-RF/MW
  - Proposes to add frequency-domain modeling to VHDL-AMS
- Trend is away from describing distributed models with equations
  - Measurements use tables of  $S$ -parameters
  - Electromagnetic solvers either use  $S$ -parameters or ROMs

- Few situations where users are comfortable writing a distributed model using expressions involving frequency
  - Skin effect:  $R = R_0 \sqrt{f}$
  - System level models:  $v_{\text{out}}(f) = v_{\text{in}}(f)$  for  $f < f_0$  and 0 otherwise
- Often models are non-physical
  - Non-causal, non-passive, etc. (ex: above models are noncausal)
  - Results in large errors and various numerical problems
  - Transient-base simulators struggle with such models
  - Harmonic balance simulators increasingly struggle
    - Envelope is time-domain based; pre-convergence transient
- Very easy and common for users to write non-physical models

# Extending AMS into Frequency-Domain



- Provide hooks to test equipment and EM solvers
  - Table models (S-parameter files) or ROMs
- Wait on providing support in language for expressions involving frequency
  - Improve simulator implementations
  - Improve frequency-domain expression language
    - Develop language that naturally avoids causality issues



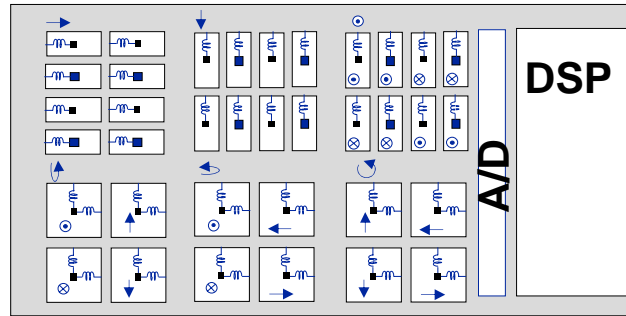
*how big can you dream?™*



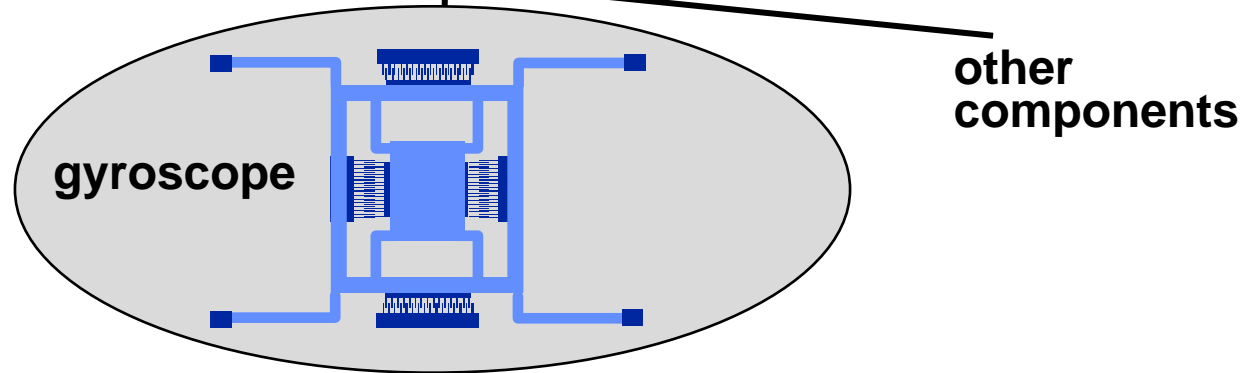
# MEMS

# Hierarchical Levels of Abstraction in Suspended MEMS

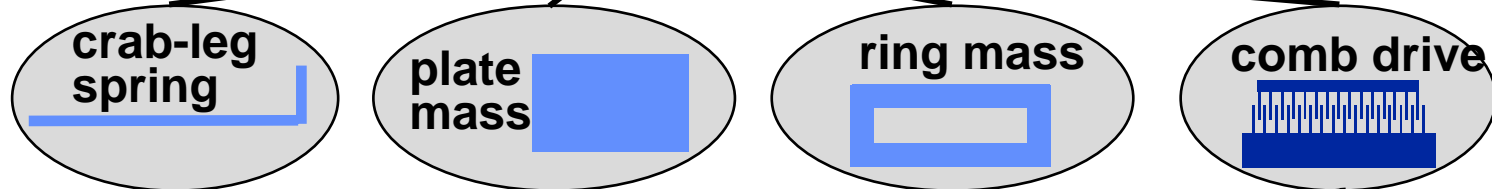
System



Component (Subsystem)



Functional element

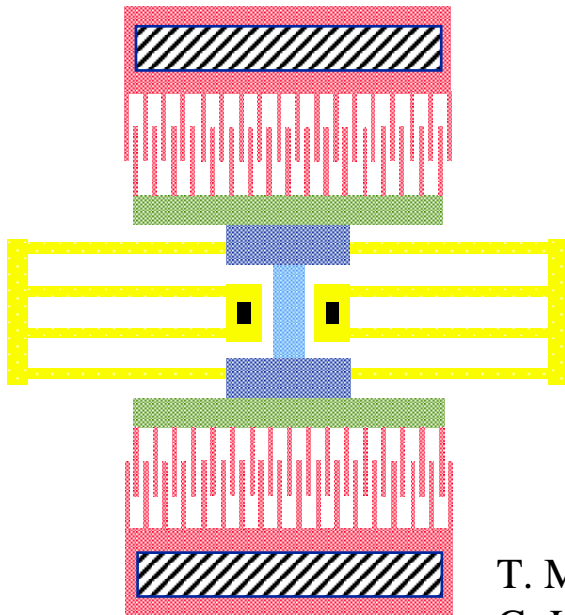


Atomic element



# NODAS MEMS Cell Library

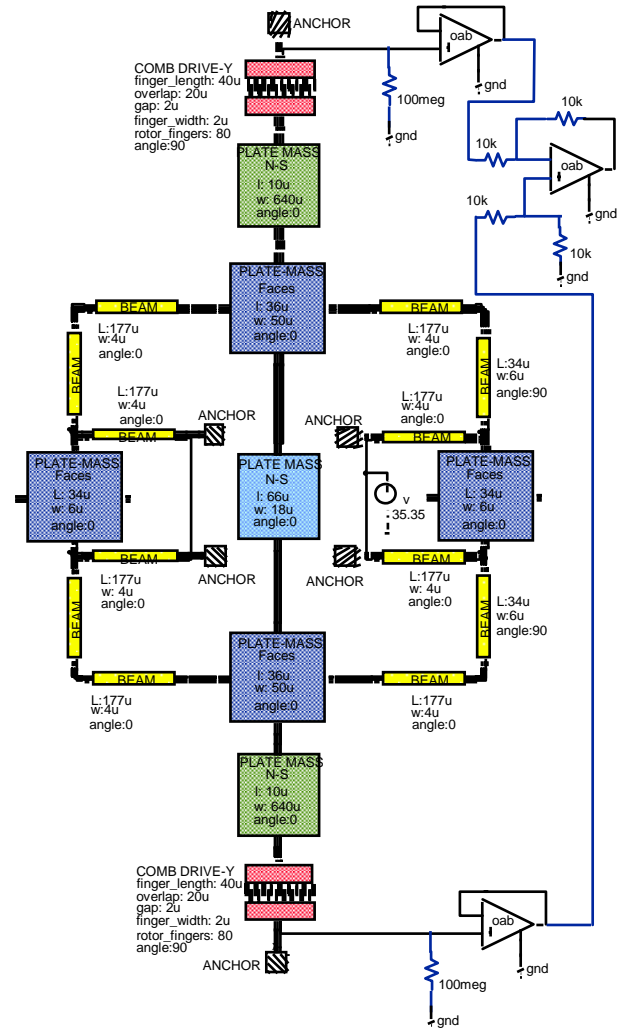
- NODAS is the MEMS schematic design library developed at Carnegie Mellon.
- Goal: Develop and validate reusable parameterized cell library and tools



layout generation



circuit extraction



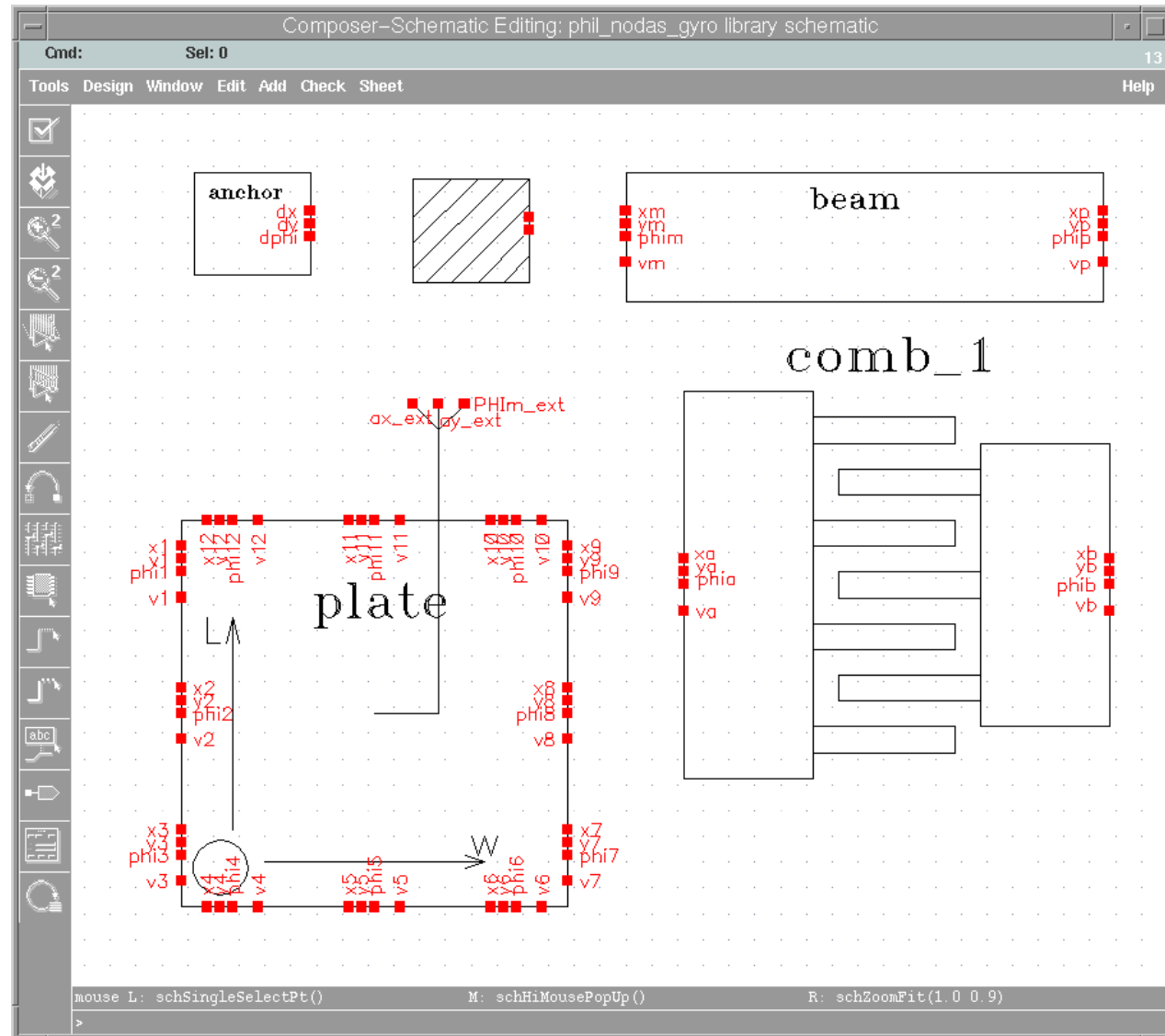
# Basic Elements

- Circuit representations of suspended MEMS can be partitioned into four basic lumped-parameter elements: plates, beams, gaps, and anchors

	PLATE	BEAM	GAP	ANCHOR
<i>symbol</i>				
<i>parameters</i>	<p>L: 50u w: 100u angle: 0</p>	<p>L: 100u w: 4u angle: 0</p>	<p>g: 4u L<sub>o</sub>: 25u angle: 0</p>	
<i>layout</i>				

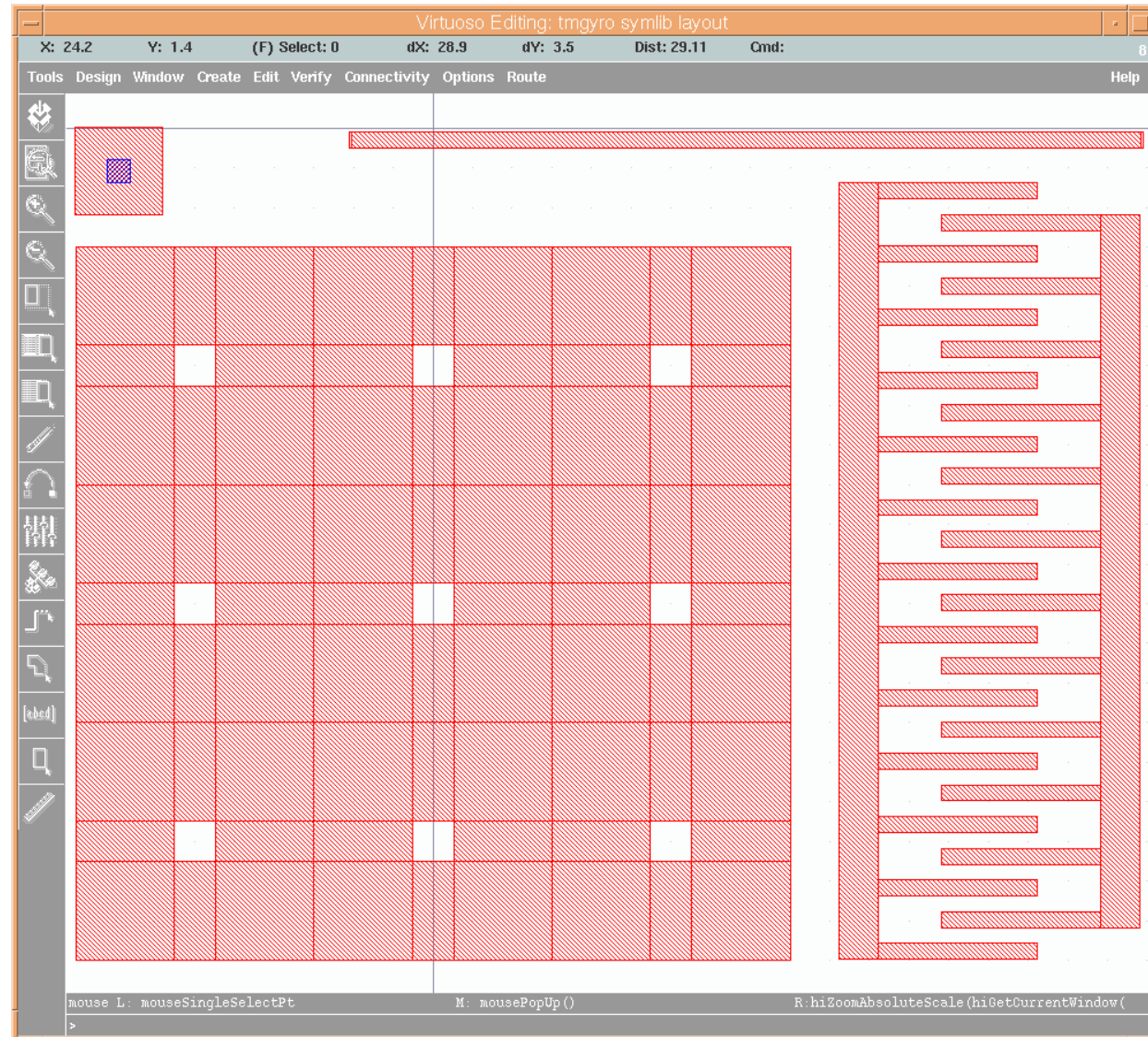
# Multi-Level Design Reuse

- Elements (symbols and models) can be reused in new designs
- Low-level elements are:
  - Anchor
  - Beam
  - Plate
  - Gap
  - Comb



# Layout Generation

- Automated layout is hierarchically p-cell (parameterized cell) driven directly from elements



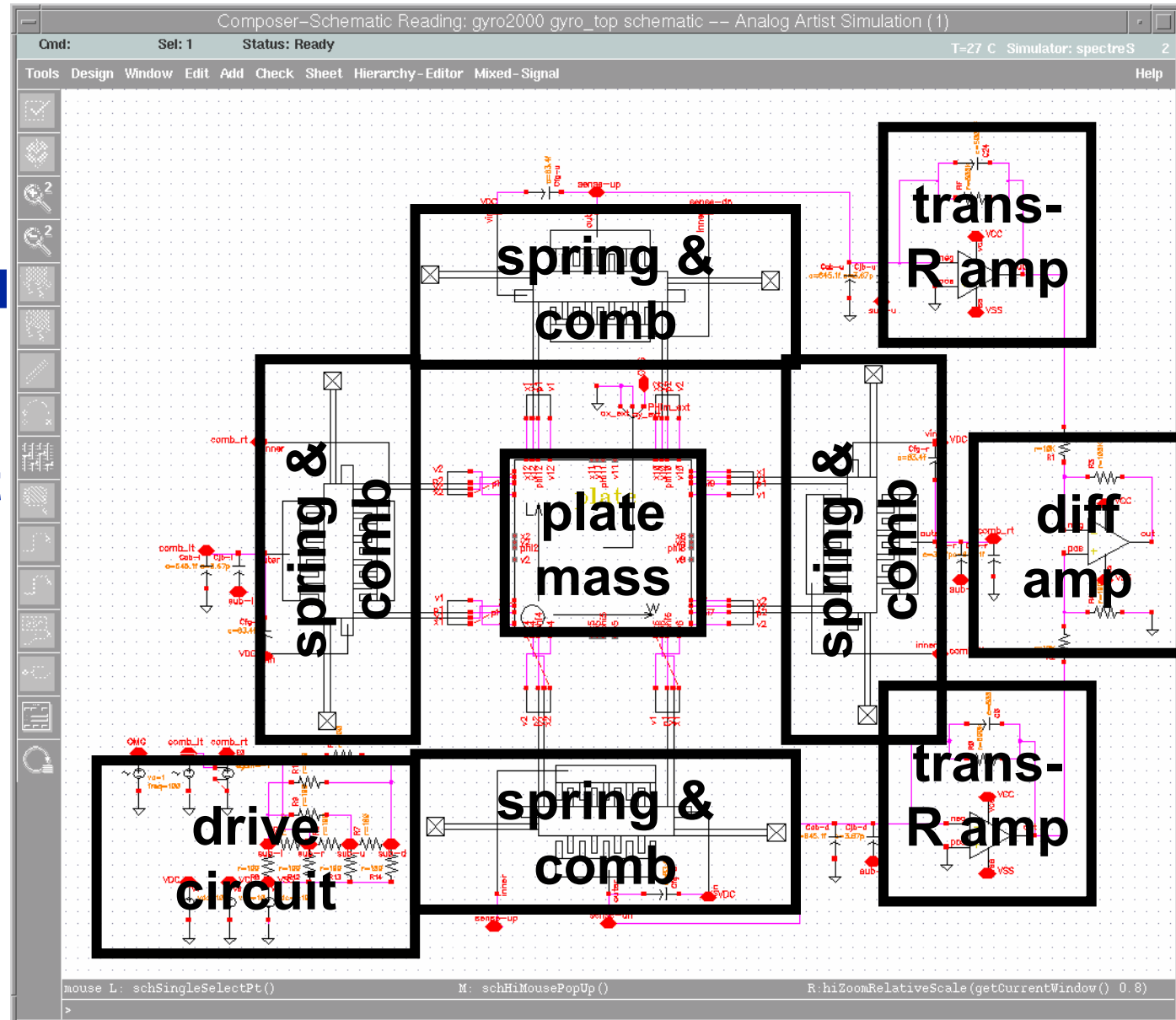
# Gyroscope Schematic Design Entry

## MEMS

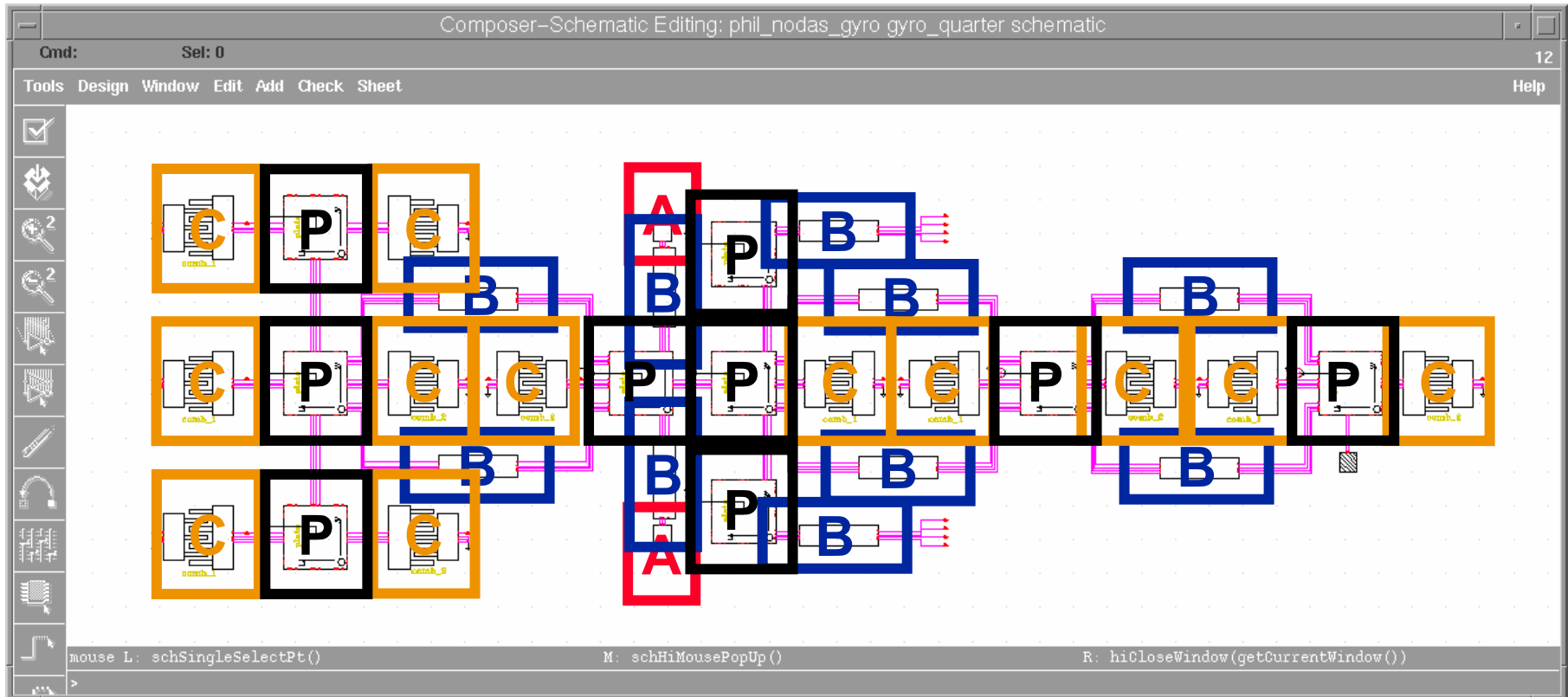
hierarchical cells provide ability to start simple and add detail later

Interoperable components at several levels of abstraction

Only two kinds of MEMS components in this view



# MEMS at Next Level: Spring & Comb Cell



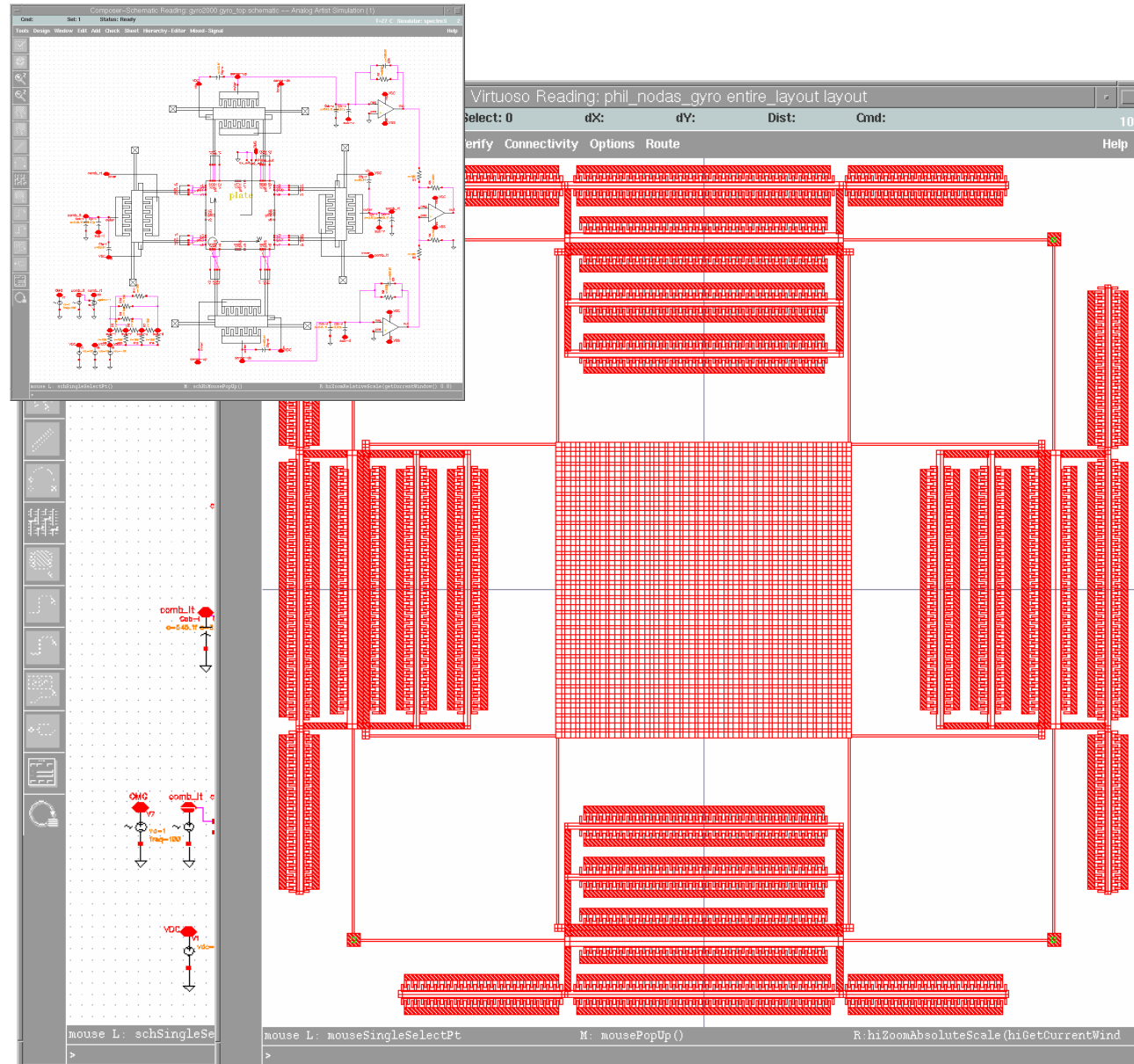
## ■ Extreme detail with only four MEMS components

- A – anchor
- B – beam
- C – comb-finger capacitor
- P – plate mass

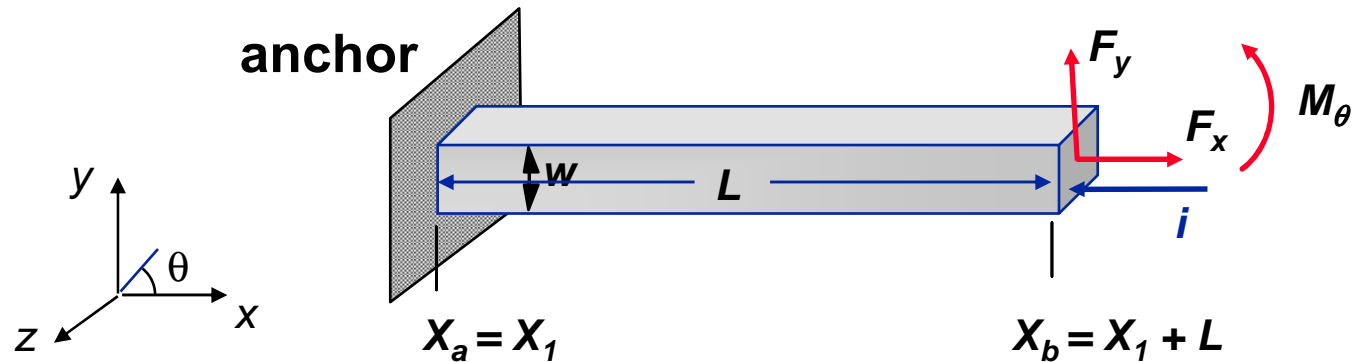


# Gyroscope Layout Generation

- All necessary geometric information embedded in schematic

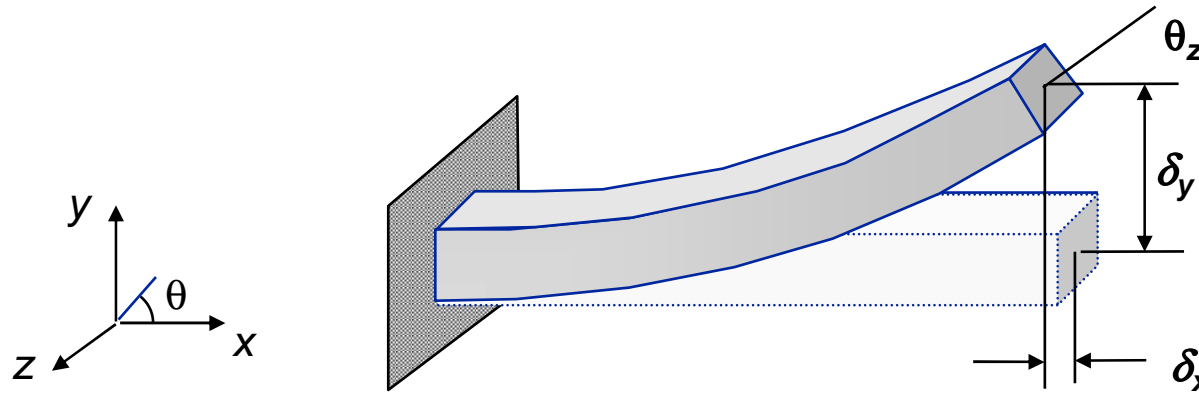


# Cantilever Beam Example



- Assume conducting beam:
  - Kirchhoff's current law (KCL)
    - $\Sigma i = 0$
- Assume 2-D operation ( $x$ - $y$  plane):
  - Force balance:
    - $\Sigma F_x = 0; \Sigma F_y = 0$
  - Moment balance:
    - $\Sigma M = 0$

# Position and Displacement



## ■ Layout position

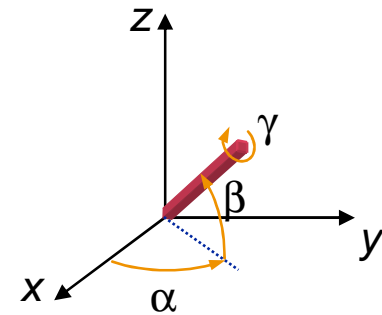
- X, Y, Z

- Orientation angles,  $\alpha, \beta, \gamma$

## ■ Displacement

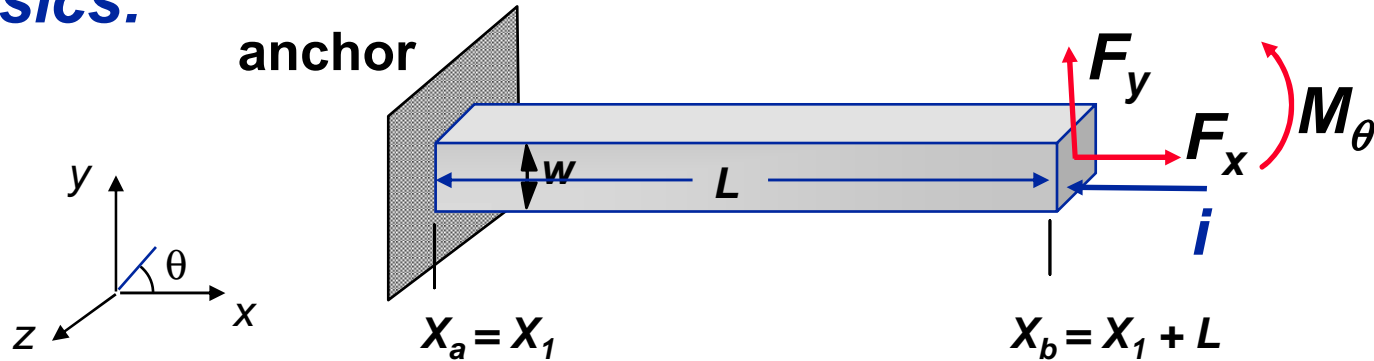
- $\delta_x, \delta_y, \delta_z$

- $\theta_x, \theta_y, \theta_z$

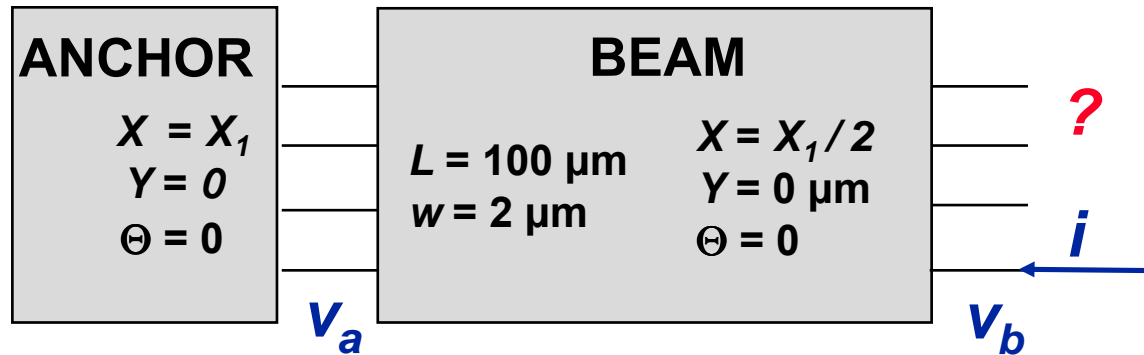


# MEMS Circuit Representation: Cantilever Beam Example

## Physics:



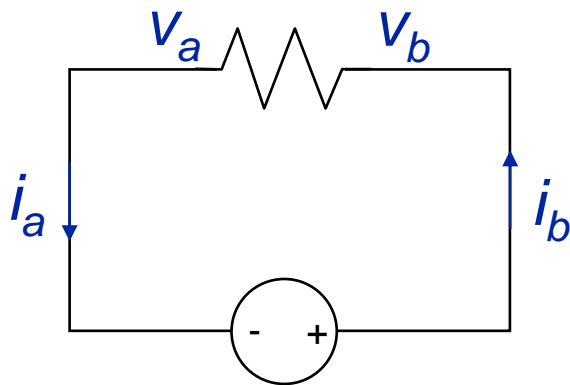
## Circuit:



Schematic components have geometric parameters

# 'Through' and 'Across' Variables

- Electrical 'across' variable is voltage
- Electrical 'through' variable is current



- Nodes are labeled  $a$  and  $b$
- Across variables are  $v_a$  and  $v_b$ 
  - Voltage 'across' resistor is  $v_b - v_a$
- Through variables are  $i_a$  and  $i_b$ 
  - Current 'through' resistor is  $i_a$  (or  $i_b$ )

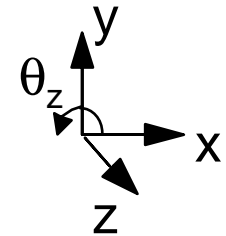
Model determines  $i_a = f(v_a, v_b)$  and  $i_b = f(v_a, v_b)$

# Mechanical Nodal Conventions

## ■ Across variables ( $x, y, \theta_z$ )

- Positive valued displacements are in positive axial direction
- Positive valued angles are counterclockwise around axis

## Example: moving beam in x



both  $x_a$  and  $x_b$  are positive

## Equivalent schematic:

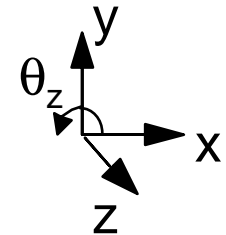


# Mechanical Nodal Conventions

## ■ Across variables ( $x, y, \theta_z$ )

- Positive valued displacements are in positive axial direction
- Positive valued angles are counterclockwise around axis

## Example: beam in tension



$x_a$  is negative;  $x_b$  is positive

## Equivalent schematic:

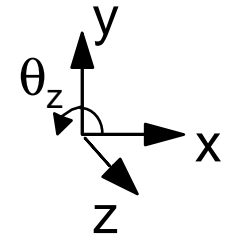
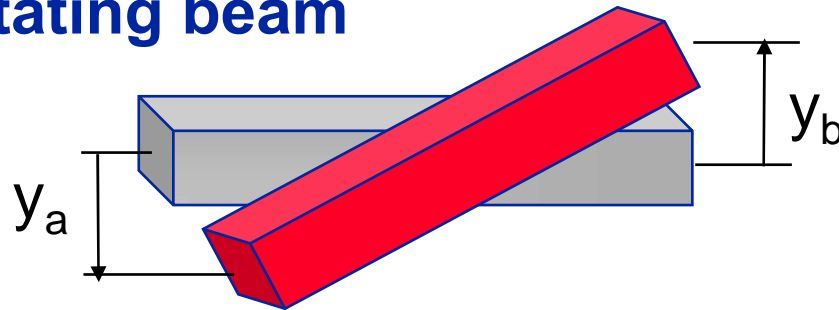


# Mechanical Nodal Conventions

## ■ Across variables ( $x, y, \theta_z$ )

- Positive valued displacements are in positive axial direction
- Positive valued angles are counterclockwise around axis

## Example: rotating beam



$y_a$  is negative;  $y_b$  is positive

## Equivalent schematic:



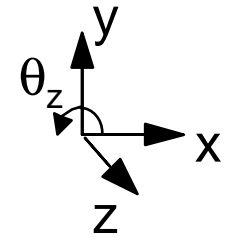
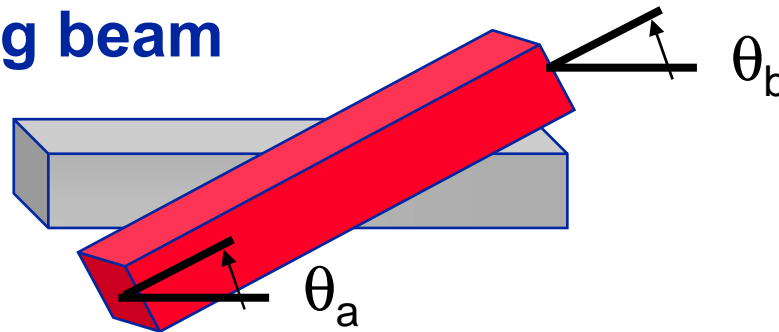


# Mechanical Nodal Conventions

## ■ Across variables ( $x, y, \theta_z$ )

- Positive valued displacements are in positive axial direction
- Positive valued angles are counterclockwise around axis

## Example: rotating beam



both  $\theta_a$  and  $\theta_b$  are positive

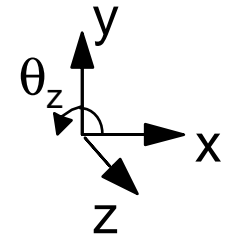
## Equivalent schematic:



# Mechanical Nodal Conventions

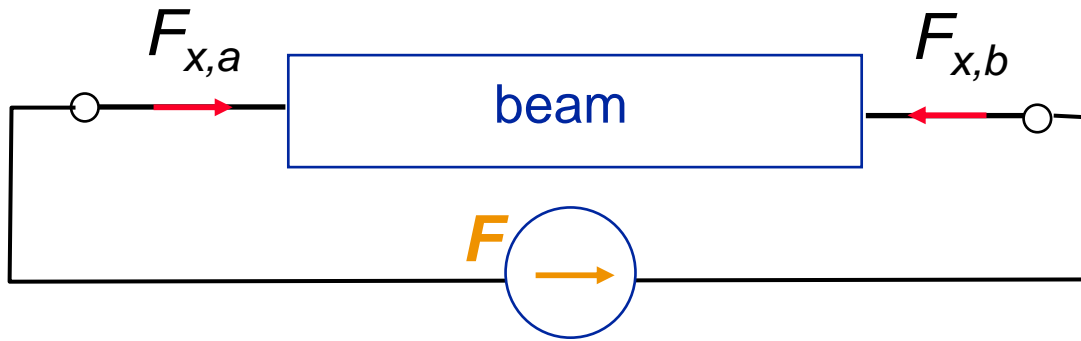
- **Through variables ( $F_x, F_y, M_z$ )**
  - Force flowing into node acts in positive axial direction
  - Moment flowing into node acts counterclockwise around axis

## Example: beam in tension



$F_{x,a}$  is negative;  $F_{x,b}$  is positive

## Equivalent schematic:



# Mechanical Nodal Conventions

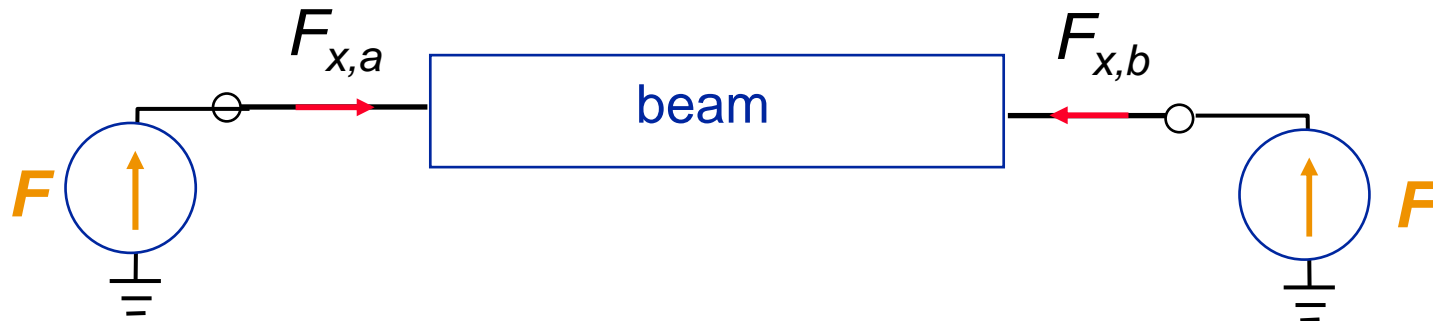
- **Through variables ( $F_x, F_y, M_z$ )**
  - Force flowing into node acts in positive axial direction
  - Moment flowing into node acts counterclockwise around axis

## Example: moving beam



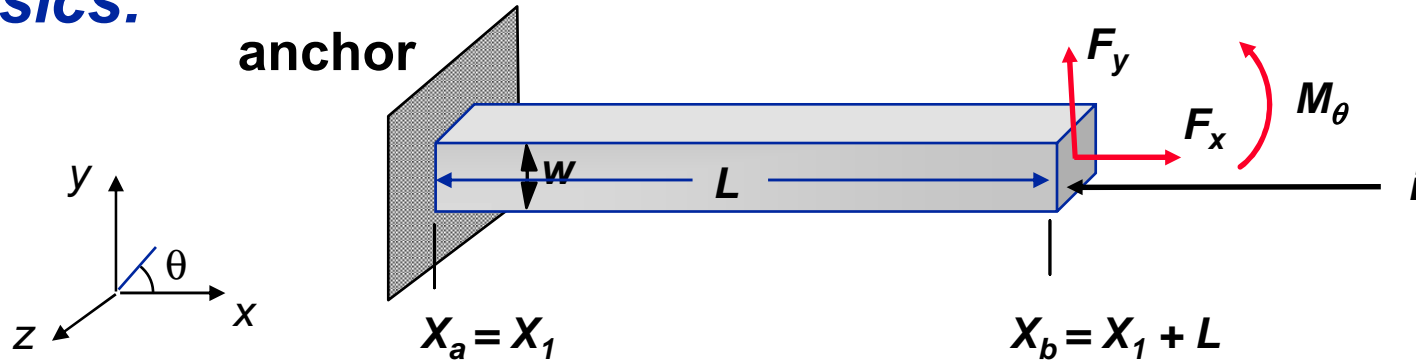
both  $F_{x,a}$  and  $F_{x,b}$  are positive

## Equivalent schematic:

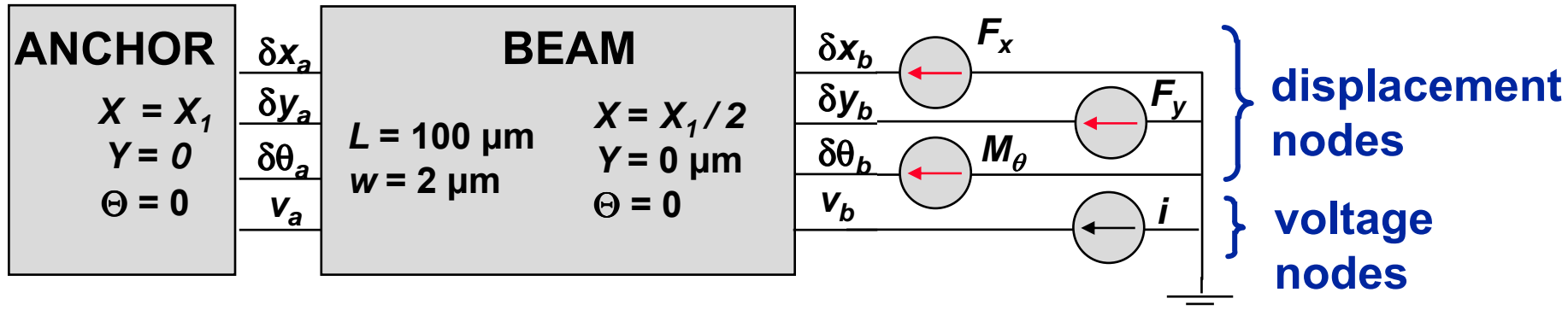


# MEMS Circuit Representation: Cantilever Beam Example

## Physics:



## Circuit:



- Across variables: displacement, angle, voltage
- Through variables: force, moment, current
- Branch relations:  $\sum i = 0$ ;  $\sum F = 0$ ;  $\sum M = 0$

# What is Needed to Support MEMS?



- Extend Verilog-A/MS to support composite, multidimensional signals ( $X$ ,  $Y$ ,  $Z$ ,  $\alpha$ ,  $\beta$ ,  $\gamma$ ,  $V$ )
- Carefully resolve tolerancing issues
  - Develop natures with appropriate tolerances, pointers to derivative and integral natures
  - Develop modeling guidelines to improve use of tolerances
  - Implement tolerancing features of language in simulators
- Develop MEMS library
- Improve visualization tools

*how big can you dream?™*



# Compact Modeling

# Issues in Compact Modeling



- BSIM3v3 requires 40k lines of code
  - Can take 1 year or more to schedule a model
  - Can take 6 months or more to implement a model
  - Can take 2 months or more to enhance a model
  - Including time to develop the model, and time to adopt release that contains it, it can take several years between when an engineer requests a model and when it is available
- Simulation vendors only support most popular models
  - Access to specialty models suffers
  - Many modeling groups struggle to contribute
  - Users must make do without the models they need

# Issues in Compact Modeling

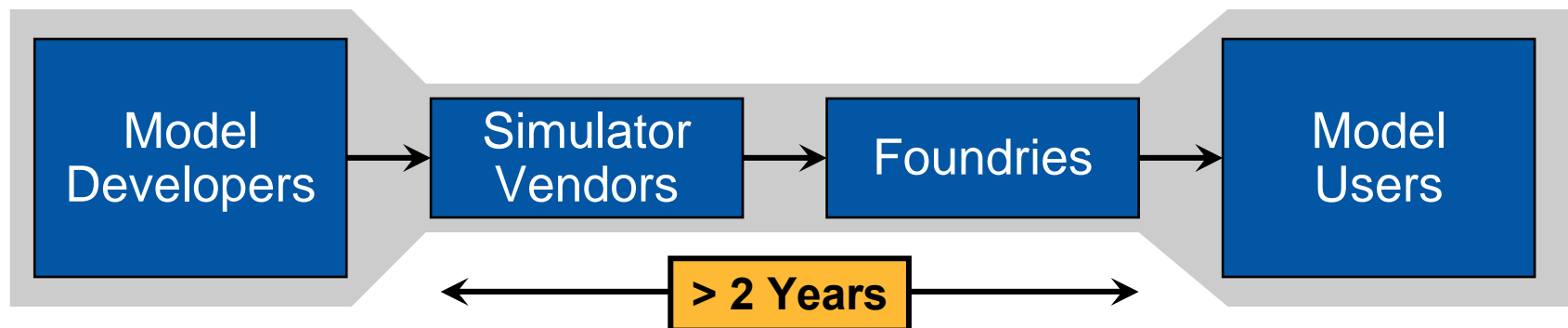


- Can take a long time to include important new effect into models
  - Leakage, RF effects, etc.
- Models inefficiently implemented
  - Models too large, implementers too rushed, to effectively optimize models
    - Difficult trade-off between efficiency and time required to implement model
  - Core functions are huge (containing more than 2500 lines for BSIM3v3)
    - Too large for optimizing compilers
  - Bloated models
    - With few models, those available must do everything



# Issues in Compact Modeling

- Slight difference in models between simulators, extractors
  - Causes extra work to extract and support multiple versions of models
  - Causes confusion, finger pointing
- There is too much distance between model developers and users
  - Takes too much time
  - Middle men are often reluctant partners with competing objectives
  - Frustrating for users (need help) and developers (want to help)



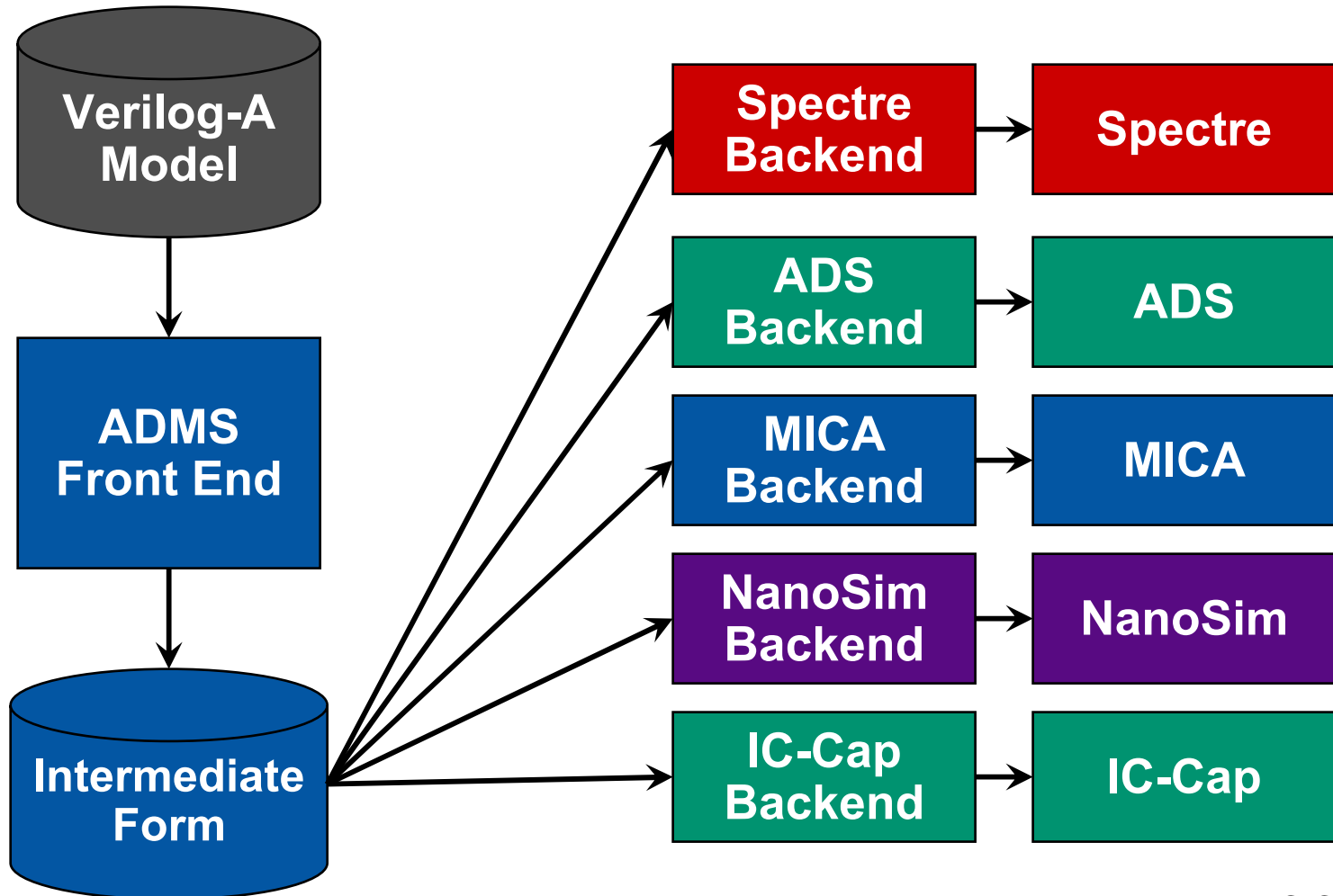
# Effect of Issues



- Few models are available
- They run slowly
- They take a long time to get
- Users have little control of what they get
- Model developers and users are disempowered, frustrated
- Models are hard to develop and establish
  - Takes the fun out of modeling
  - Makes it hard to recruit new talent to the field

- Develop models in Verilog-A
  - It's easy to use (a language that is designed for modeling)
  - Make and try changes with quick turn around time
  - Works in all analyses (DC, AC, noise, transient, RF, etc.)
  - Test models on real circuits (ring oscillators, etc.)
- Compile in to multiple simulators
  - Exactly the same model for all simulators & extractors
  - Expect better than hand-coded performance (eventually)
  - Avoids errors that result during conversion to C
- Eliminates middle men, empowers model developers and users
  - Encourages open-source model development

# Motorola's ADMS



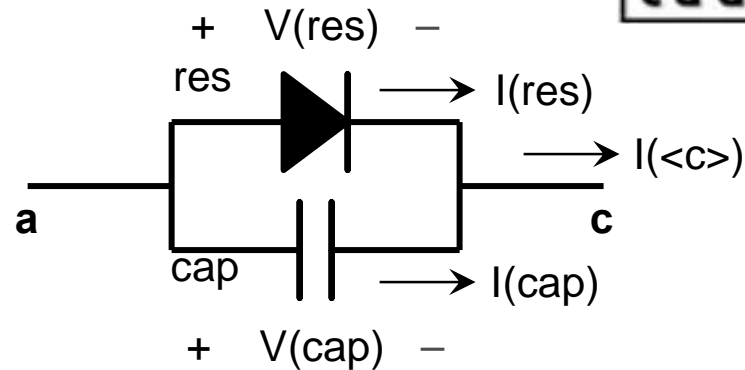
Lemaitre, CICC 2002

# Why Verilog-A



- It's a good fit
  - It's a language designed for modeling
  - Compatible with SPICE-class simulators, does not require full MS simulator
- It's a standard
  - It is not proprietary, can be implemented & supported by anybody
  - Behavioral model benefit from association with compact models
    - Compilers, optimizers, documentation, etc.
  - Compact model benefit from association with behavioral models
    - Increased attention and investment
  - More people will know language
- Rapid testing of models
  - Interpreted versions exist
  - Modify and test model without compiling

# Example: Diode



```
module diode (a, c);
```

```
    electrical a, c;
```

```
    branch (a, c) res, cap;
```

```
    parameter real is = 1e-14 from (0:inf);
```

```
    // resistive parameters
```

```
    parameter real tf = 0, cjo = 0, phi = 0.7;
```

```
    // capacitive parameters
```

```
    parameter real kf = 0, af = 1, ef=1;
```

```
    // noise parameters
```

```
    analog begin
```

```
        I(res) <+ is*(limexp(V(res)/$vt) - 1);
```

```
        I(cap) <+ ddt(tf*I(res) - 2*cjo*sqrt(phi*(phi*V(cap))));
```

```
        I(res) <+ white_noise(2*'P_Q'*I(res));
```

```
        I(res) <+ flicker_noise(kf*pow(I(res), af), ef);
```

```
    end
```

```
endmodule
```

**One Simple Model Works in All Analyses**  
— DC, AC, Noise, Transient, RF —

# Extending Verilog-A



- Improved documentation
  - Model, parameters, terminals, etc.
- Modular model support
  - Declare variables where used
  - Define multiple versions with same parameters but different speed/accuracy tradeoffs
  - Allow user to easily specify version as configuration
- Optional terminals
- Required parameters
- Initialized variables
- Output, op-point parameters
- Multiplicity factor
- Gmin support
- Frequency-domain descriptions.
- Simulator specificity

- Multiple simulator & extractor support
  - Need a compelling set of simulators & extractors supported
  - Model writers must believe that their models will see substantial use
  - Foundries, users must see compelling advantage to switch
    - Reduced model support costs
    - Improved model quality, performance, coverage, accuracy, timeliness, ...
- Available Models
  - Need a compelling set of models available in Verilog-A
  - Would be best if they were exclusively available in Verilog-A



# If We Are Successful



- More nimble model development and support process
  - Companies can ask local universities to develop specialized models
  - Model fixes can be turned around in hours
  - Will be important if models begin to change at  $< 90\text{nm}$
- A healthier, more open modeling community
  - Enables an open-source approach to development and support
  - Allows more people to contribute
  - Allows compact modeling to expand beyond MOS and BJT models

*how big can you dream?™*



**Onward ...**

# Looking Back



- As a community, we have accomplished a great deal
  - Standard languages
  - Simulators
  - Model libraries
  - IP libraries
- While you are here ...
  - Take time to celebrate all that we have accomplished

# Looking Forward



- We still have much to do
  - Improve the languages, tools and libraries
  - Educate the masses
  - Branch out into new areas
  - Automate the model generation process ???
- If we are successful, we will have accomplished something great
  - We will have changed the way design and simulation are done
  - Remember to occasionally step back and look at the big picture
  - Admire it, then do something to make it better



*how big can you dream?™*